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SUBSTITUTE FORM PTO-1449 (MODIFIED)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 06618/021001		Sheet 1 of 1 SERIAL NO. 06618/021001	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				APPLICANT: Orly Yadid-Pecht et al.			
				FILING DATE November 7, 1996		GROUP	
(37 CFR 1.98(b))							

U.S. PTO
09/654922
09/05/96

U.S. PATENT DOCUMENTS											
EXAMINER INITIAL		PATENT NUMBER							ISSUE DATE	PATENTEE	CLASS SUBCLASS
RMJ	AA	5	2	7	4	4	5	9	12/28/93	Hamasaki Masaharu	
RMJ	AB	5	4	8	5	2	0	6	01/16/96	Nakagawa Eigo et al.	
	AC										
	AD										
	AE										
	AF										
	AG										
	AH										
	AI										
	AJ										
	AK										

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION								
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
Rmt	AL	EP 0599570	06/01/94	Europe				
Rmj	AM	EP 0300365	01/25/89	Europe				
Rmj	AN	JP 06030186	02/04/94	Japan				
	AO							
	AP							

OTHER DOCUMENTS (including Author, Title, Date, Place of Publication)									
	AQ								
	AR								
	AS								

EXAMINER <i>Robert M. L. L.</i>	DATE CONSIDERED <i>7/9/94</i>
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(Use several sheets if necessary)APPLICANT:
Yadid-Pecht et al.FILING DATE
11/7/96GROUP
2504

(37 CFR 1.98(b))

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER							ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Ent</i>	AA	5	4	7	1	5	1	5	11/28/95	Fossum et al.	677	60	
<i>Long</i>	AB	5	5	4	1	4	0	2	7/30/96	Ackland et al.	250	208	
<i>Long</i>	AC	5	5	7	6	7	6	3	11/19/96	Ackland	348	308	
	AD												
	AE												
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	AG												
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	AJ												
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FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER DOCUMENTS (including Author, Title, Date, Place of Publication)

<i>Ent</i>	AQ	Fossum et al. Application of the Active Pixel Sensor Concept to Guidance and Navigation, SPIE, Vol. 1949 paper 30 (1993)						
<i>Long</i>	AR	Mendis et al., CMOS Active Pixel Image Sensor, IEEE Transactions on Electronics Devices, 41(3) 452-453						
<i>Long</i>	AS	Mendis et al., Progress in CMOS Active Pixel Image Sensors, SPIE Vol.2172:1-11 (1994)						

EXAMINER

Rahon M. Miller

DATE CONSIDERED

7/9/04

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SUBSTITUTE FORM PTO-1449
(MODIFIED)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
06816/02100SERIAL NO.
08/744,494INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(Use several sheets if necessary)APPLICANT:
ORLY YADID-PECHT AND ERIC R. FOSSUMFILING DATE
11/7/96

GROUP

(37 CFR 1.98(b))

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER							ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>Rut</i>	AA	5	2	6	4	9	4	4	11/23/93	Y. Takemura	358	335	03/29/91
	AB	4	9	5	9	7	2	3	09/25/90	S. Hashimoto	358	213.11	11/02/88
	AC	5	1	6	2	9	1	4	11/10/92	K. Takahashi et al.	358	213.19	10/19/90
	AD	4	7	0	6	1	2	3	11/10/87	J. Chautemps	358	213.19	04/07/86
	AE	5	0	8	4	7	0	4	01/28/92	W. Parrish	341	184	02/02/90
<i>Rut</i>	AF	4	8	1	9	0	7	0	04/04/89	J. Hynecek	358	213.11	04/10/87
	AG												
	AH												
	AI												
	AJ												
	AK												

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							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER DOCUMENTS (including Author, Title, Date, Place of Publication)

<i>Rut</i>	AQ	Hyomasu, M. A New MOS Imager Using Photodiode as Current Source, IEEE Journal of Solid-State Circuits, Vol. 26, No. 8, August 1991.						
	AR							
	AS							

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